

intensity of the specularly reflected beam (by conservation of current) but which do not affect the secondary current. Fig. 2 shows the total secondary current as well as the specularly reflected intensity for one quadrant of the rotation diagram about the (660) reflection. The minima in the secondary emission are associated with the geometry for the excitation of low index Laue reflections. The minimum in the specular reflection about the (002) orientation is due to a Bragg reflection and is not accompanied by a reduction in the secondary emission. In both Figures the strong minima occur for the excitation of Laue reflection belonging to the (110) zone.

The maxima in the reflected intensity, which occur when the incident plane is parallel to a low index plane of the crystal are partially an artifact due to the lack of Laue reflections which can be excited near to these orientations, and may also, in part, be due to a dynamical mechanism similar to that of the blocking observed for the scattering of heavy particles in these directions (Erginsoy, Datz, Leibfried & Lutz, 1967). The orientations of these low index planes also correspond to the centers of the Kikuchi bands associated with the same planes (Baudoing, Stern & Taub, 1968). The loci of the incident beam directions for the excitation of a Laue reflection (The Brillouin zone boundaries) are just the directions of the Kikuchi lines diffracted from the planes of the same index (optical reversibility or reciprocity theorem). A detailed analysis of rotation diagrams will appear elsewhere (Stern, 1968; Stern, Taub & Gervais, 1969; Stern, Gervais & Taub, 1969).

References

- BETHE, H. A. (1928). *Ann. Phys.* **85**, 55.
 BAUDOING, R., STERN, R. M. & TAUB, H. (1968). *Surface Sci.* **11**, 255.
 DATZ, S., ERGINSOY, C., LEIBFRIED, G. & LUTZ, H. O. (1967). *Ann. Rev. Nucl. Sci.* **17**, 129 and references contained therein.
 GERVAIS, A., STERN, R. M. & MENES, M. (1968). *Acta Cryst.* **A24**, 191.
 NIEHRS, H. (1954). *Z. Phys.* **139**, 88.
 STERN, R. M., PERRY, J. & BOUDREAUX, D. S. (1969). *Rev. Mod. Phys.* To be published in April.
 STERN, R. M. (1968). *Proc. Amer. Cryst. Ass.* **4**, 14.

Acta Cryst. (1969). **A25**, 394

Diffraction symbols. Erratum. By J. D. H. DONNAY, *Crystallographic Laboratory, The Johns Hopkins University, Baltimore, Maryland 21218, U.S.A.* and OLGA KENNARD, *University Chemical Laboratory, Cambridge, England*

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In the paper published under the above title (Donnay & Kennard, 1964), please restore omitted words as follows:
 Page 1340, column 1, line 3 up: *after the word aspect, insert P3_{1,2}** into.*

Note also that the space-group symbols used in this paper are those of the 1935 edition of the International Tables. Any screw axis that results from intersecting symmetry planes need not be explicitly symbolized, although this was done in the 1952 edition. Examples: $P4mc = P4_2mc$, $14md =$

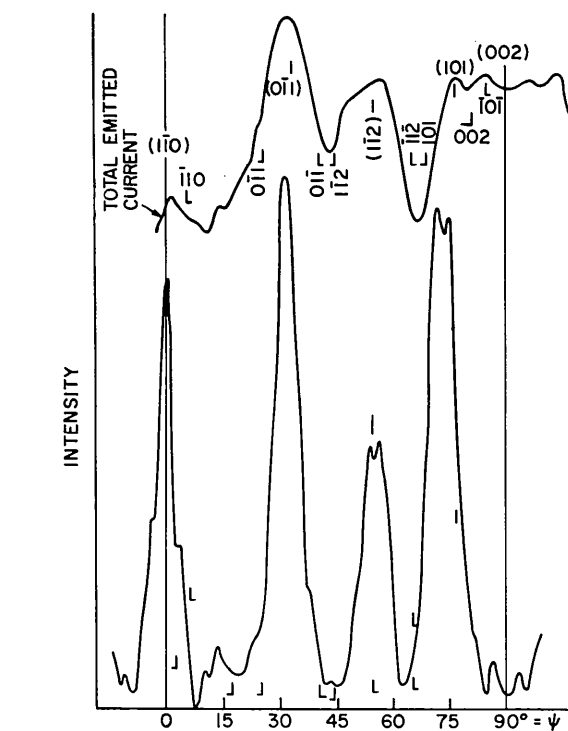


Fig. 2. Lower curve: Rotation diagram about the 660 reflection, $2\theta = 65^\circ$, $V = 825$ volts. Upper curve: total emitted secondary electron current as a function of azimuthal angle. The orientation of the dense planes of the (110) zone are indicated by short vertical lines. The orientation of the plane of incidence for the excitation of Laue reflections are shown by | and J, which bracket each of the low index planes. These orientations correspond to the position of the pair of Kikuchi lines from these planes.

- STERN, R. M., GERVAIS, A. & TAUB, H. (1969). Submitted to *Surface Sci.*
 STERN, R. M. & TAUB, H. (1968). *Phys. Rev. Letters*, **24**, 1340.
 STERN, R. M., TAUB, H. & GERVAIS, A. (1969). In *Structure and Chemistry of Solid Surfaces*. Ed. by G. SOMORJAI. New York: John Wiley.

14_1md , $Pbc2 = Pbc2_1$. The subscripts can easily be added by those who prefer the more explicit symbolism. We feel an explanation is in order, in view of the correspondence we received on this particular point.

Reference

- DONNAY, J. D. H. & KENNARD, O. (1964). *Acta Cryst.* **17**, 1337.